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- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Operating Range 2-V to 5.5-V V_{CC}
- Package Options Include Plastic Small-Outline Transistor (DBV, DCK) Packages

DBV OR DCK PACKAGE (TOP VIEW)



description

This device contains a single 2-input NOR gate that performs the Boolean function $Y = \overline{A} \cdot \overline{B}$ or $Y = \overline{A} + \overline{B}$ in positive logic.

The SN74AHC1G02 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

l	INP	JTS	OUTPUT
l	Α	В	Υ
ı	н х		L/
ı	X	Н	o L
	L	L	Н

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



SN74AHC1G02 SINGLE 2-INPUT POSITIVE-NOR GATE

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input voltage range, V _I (see Note 1)	
Output voltage range, V _O (see Note 1)	\dots -0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$)	
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±25 mA
Continuous current through V _{CC} or GND	±50 mA
Package thermal impedance, θ_{JA} (see Note 2): DBV package	347°C/W
DCK package	389°C/W
Storage temperature range, T _{stq}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

			MIN	MAX	UNIT
Vcc	Supply voltage		2	5.5	V
		V _{CC} = 2 V	1.5		
V_{IH}	High-level input voltage V _{CC} = 3 V	2.1		V	
		V _{CC} = 5.5 V	3.85		
V _{IL}		V _{CC} = 2 V		0.5	
V_{IL}	Low-level input voltage	V _{CC} = 3 V		0.9	V
		V _{CC} = 5.5 V		1.65	
٧ _I	Input voltage		0	5.5	V
٧o	Output voltage		0	VCC	V
		V _{CC} = 2 V		-50	μΑ
IOH	High-level output current $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		-4	mA
		$V_{CC} = 5 V \pm 0.5 V$		-8	
		V _{CC} = 2 V		50	μΑ
IOL	Low-level output current $ V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V} $ $ V_{CC} = 5 \text{ V} \pm 0.5 \text{ V} $			4	A
				8	mA
A±/A>.	Input transition rise or fall rate $ \frac{V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}}{V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}} $			100	ns/V
Δt/Δv				20	115/ V
TA	Operating free-air temperature		-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



SN74AHC1G02 SINGLE 2-INPUT POSITIVE-NOR GATE

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Voc	T _A = 25°C			MIN	MAX	UNIT	
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	IVIIIV	IVIAA	ONIT	
		2 V	1.9	2		1.9			
	I _{OH} = -50 μA	3 V	2.9	3		2.9			
Voн		4.5 V	4.4	4.5		4.4		V	
	I _{OH} = -4 mA	3 V	2.58			2.48			
$I_{OH} = -4 \text{ mA}$ 3 V 2.58 $I_{OH} = -8 \text{ mA}$ 4.5 V 3.94 $I_{OL} = 50 \mu\text{A}$ 3 V	3.94			3.8					
	I _{OL} = 50 μA	2 V			0.1		0.1		
		3 V			0.1		0.1		
VoL		4.5 V			0.1		0.1	V	
	I _{OL} = 4 mA	3 V			0.36		0.44		
	IOL = 8 mA	4.5 V			0.36		0.44		
lı	$V_I = V_{CC}$ or GND	0 V to 5.5 V			±0.1		±1	μΑ	
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			1		10	μΑ	
Ci	$V_I = V_{CC}$ or GND	5 V		4	10		10	pF	

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	LOAD CAPACITANCE	T _A = 25°C			MIN	MAX	UNIT
PARAMETER	(INPUT)			MIN	TYP	MAX	IVIIIN	IWAX	UNIT
tPLH	tPLH A or B	Y	C _L = 15 pF		5.6	7.9	1	9.5	ns
tPHL					5.6	7.9	1	9.5	
tPLH	A or B	Y	C _L = 50 pF		8.1	11.4	1	13	
tPHL					8.1	11.4	1	13	ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

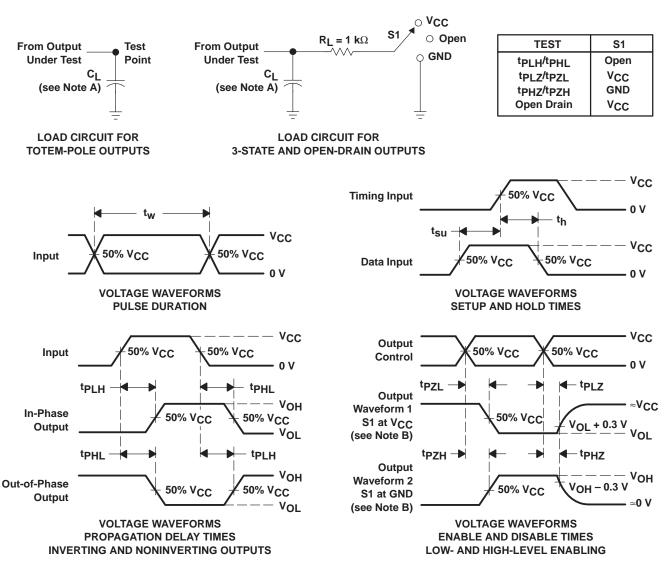
PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	T _A = 25°C			MIN	MAX	UNIT
FARAMETER				MIN	TYP	MAX	IVIIIN	WAA	ONIT
t _{PLH}	A or B	Y	C _L = 15 pF		3.6	5.5	1	6.5	ns
t _{PHL}					3.6	5.5	1	6.5	115
tPLH	A or B	V	C. 50 pF		5.1	7.5	1	8.5	20
t _{PHL}		ſ	C _L = 50 pF		5.1	7.5	1	8.5	ns

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

	PARAMETER		ONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load,	f = 1 MHz	15	pF



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \,\Omega$, $t_f \leq 3$ ns. $t_f \leq 3$ ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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